



Description

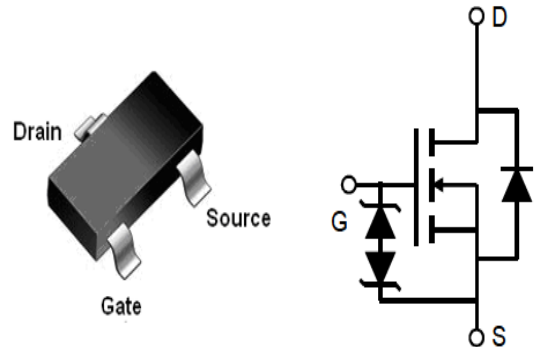
The XPX15N300AS is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

General Features

VDS =300V, ID =1.5A
RDS(ON) <3.0Ω@ VGS=10V

Application

Uninterruptible Power Supply(UPS)
Power Factor Correction (PFC)



SOT23-3L

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
XPX15N300AS	SOT-23-3L	MC3-2A	3000

Absolute Maximum Ratings (T_c=25°C unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	VDSS	300	V
Continuous Drain Current	I _D	1.5	A
Pulsed Drain Current	IDM	12	A
Gate-Source Voltage	VGSS	±20	V
Single Pulse Avalanche Energy	E _{AS}	30	mJ
Avalanche Current	IAR	1.9	A
Repetitive Avalanche Energy	E _{AR}	0.9	mJ
Power Dissipation (T _c = 25°C)	P _D	35.2	W
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55~+150	°C
Thermal Resistance, Junction-to-Case	R _{thJC}	3.55	°C/W
Thermal Resistance, Junction-to-Ambient	R _{thJA}	60	

300V N-Channel Enhancement Mode MOSFET
Electrical Characteristics (T_A=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	300	--	--	V
VGS(th)	Gate-Source Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	--	4.0	V
RDS(on)	Drain-Source On-Resistance (Note3)	V _{GS} = 10V, I _D = 1.5A	--	3.0	4.0	Ω
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 300V, V _{GS} = 0V, T _J = 25°C	--	--	1	μA
		V _{DS} = 240V, V _{GS} = 0V, T _J = 125°C	--	--	100	
IGSS	Gate-Source Leakage	V _{GS} = ±25V	--	--	±100	nA
C _{iss}	Input Capacitance	V _{GS} = 0V, V _{DS} = 25V, f = 1.0MHz	--	127	--	pF
C _{oss}	Output Capacitance		--	30	--	
C _{rss}	Reverse Transfer Capacitance		--	5	--	
Q _g	Total Gate Charge	V _{DD} = 240V, I _D = 3.0A, V _{GS} = 10V	--	4.4	--	nC
Q _{gs}	Gate-Source Charge		--	0.7	--	
Q _{gd}	Gate-Drain Charge		--	2	--	
td(on)	Turn-on Delay Time	V _{DD} = 150V, I _D = 3.0A, R _G = 25 Ω	--	18	--	ns
t _r	Turn-on Rise Time		--	55	--	
td(off)	Turn-off Delay Time		--	60	--	
t _f	Turn-off Fall Time		--	55	--	
I _S	Continuous Body Diode Current	T _C = 25 °C	--	--	3	A
ISM	Pulsed Diode Forward Current		--	--	12	
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _S = 3A, di _F /dt =100A/μs	--	250	--	ns
Q _{rr}	Reverse Recovery Charge		--	1.8	--	μC
V _{SD}	Body Diode Voltage	T _J = 25°C, I _{SD} = 3A, V _{GS} = 0V	--	--	1.4	V

Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. I_{AS} = 1.9A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25 °C
3. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%

Typical Characteristics T_J = 25°C, unless otherwise noted

Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

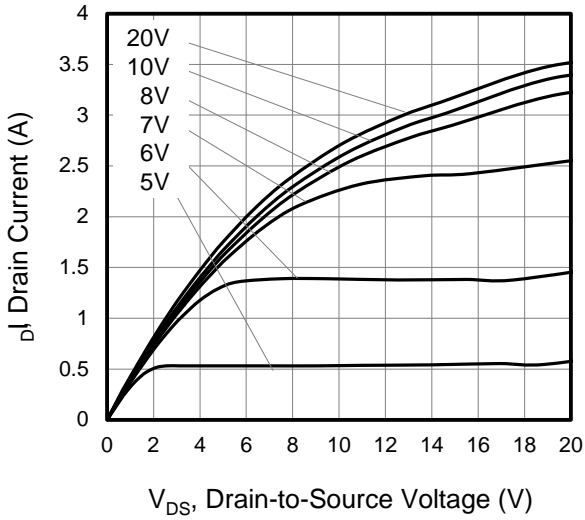
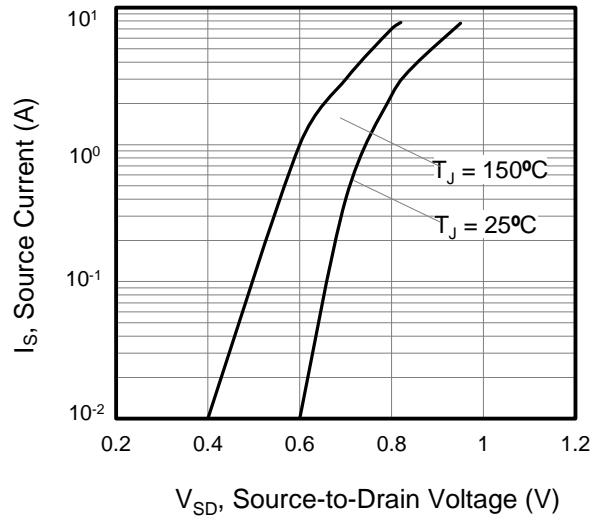
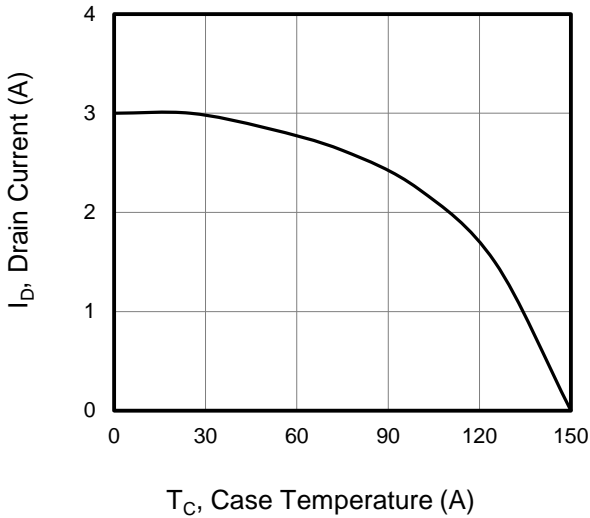
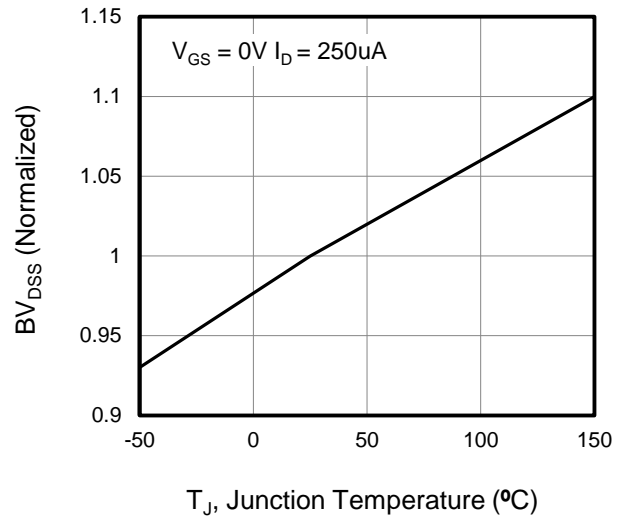
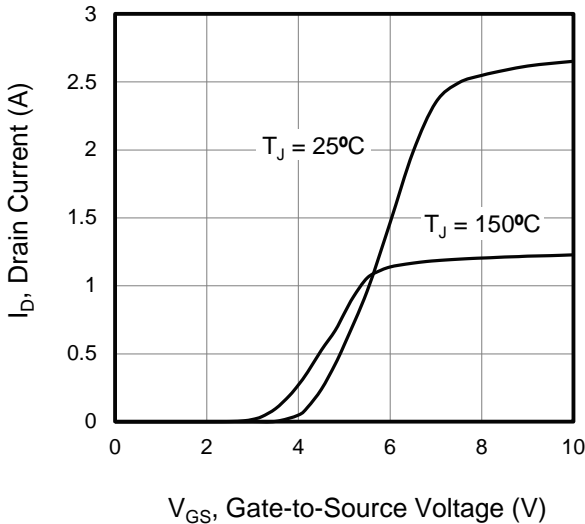
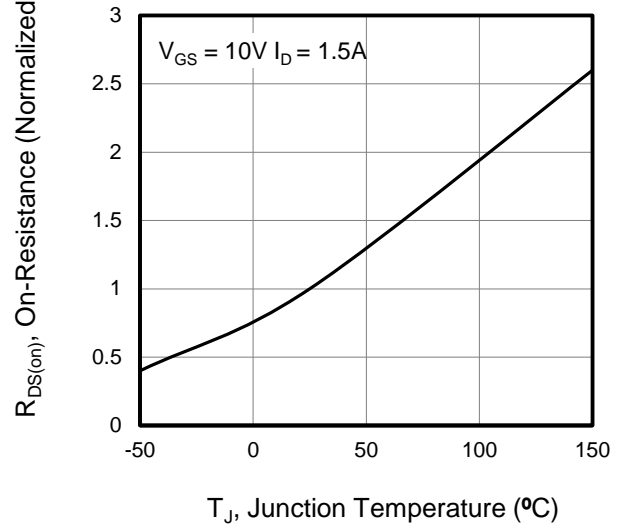
Figure 1. Output Characteristics ($T_J = 25^\circ\text{C}$)

Figure 2. Body Diode Forward Voltage

Figure 3. Drain Current vs. Temperature

Figure 4. BV_{DSS} Variation vs. Temperature

Figure 5. Transfer Characteristics

Figure 6. On-Resistance vs. Temperature


Figure 7. Capacitance

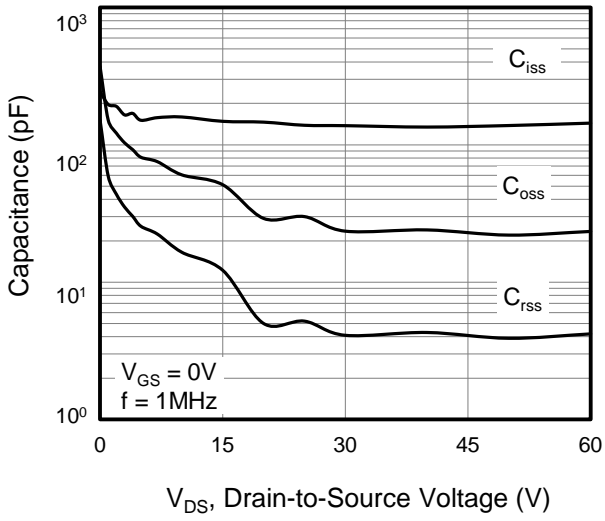


Figure 8. Gate Charge

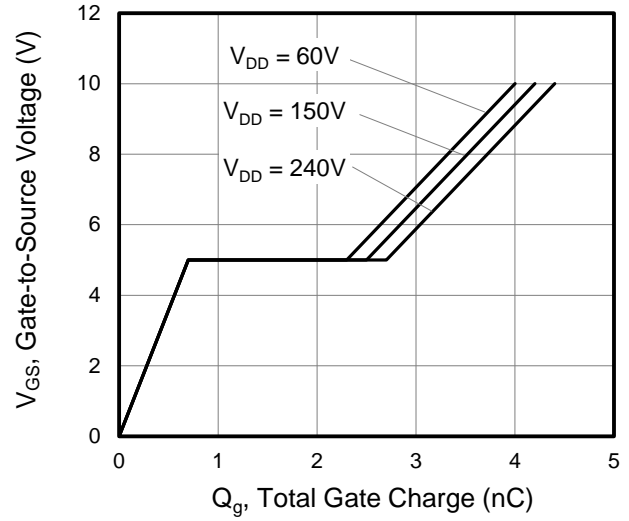
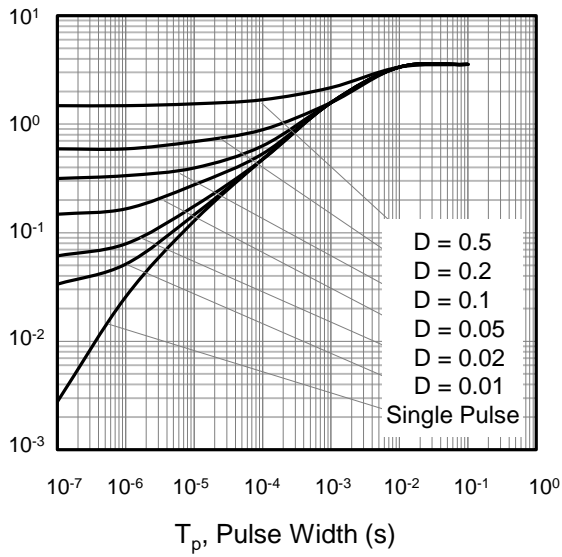
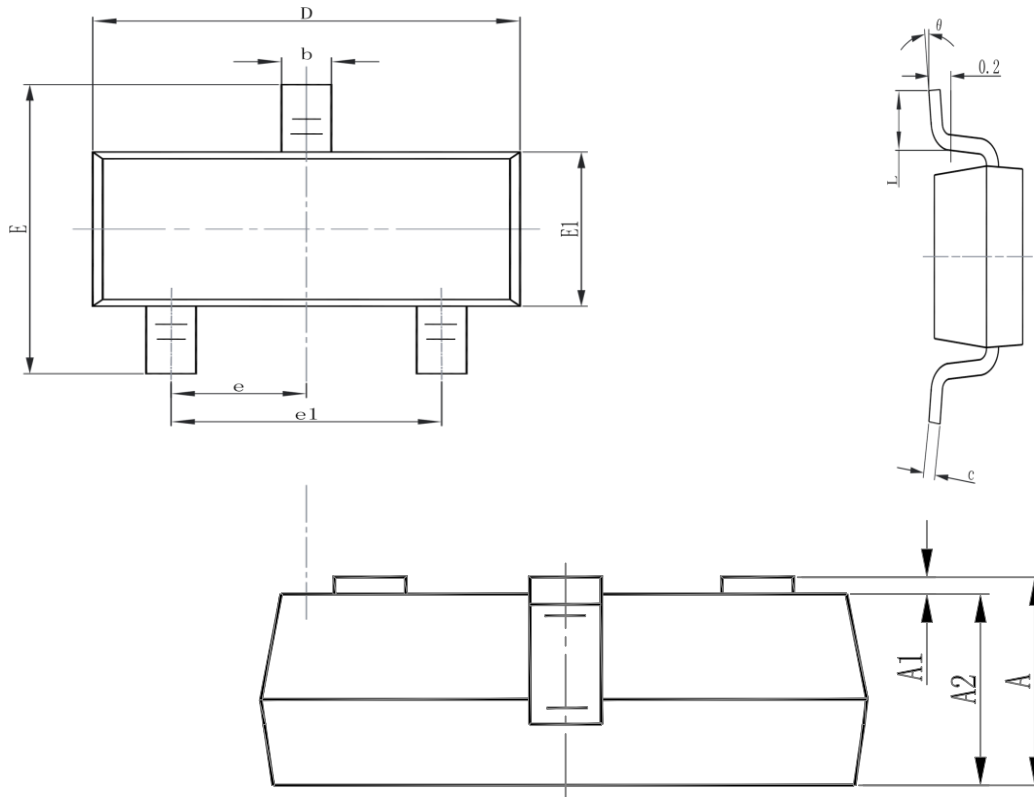


Figure 9. Transient Thermal Impedance



Package Mechanical Data-SOT23-3


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
c	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
e	0.950(BSC)		0.037(BSC)	
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°

300V N-Channel Enhancement Mode MOSFET

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C ±5°C	5sec±1sec
Pb-Free device	260°C +0/-5°C	5sec±1sec



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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